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#26 IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Filing Date June 22, 2000 Inventor John T. Moore Assignee Micron Technology, Inc. Examiner Pham, T. Attorney's Docket No. MI22-1384 Title: Methods of Forming Oxide Regions Over Semiconductor Substrates

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed after the filing of the Request for Continued Examination (RCE) Application and before receipt of the first Office Action. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee. **FAX RECEIVED**

Citation of these references is respectfully requested.

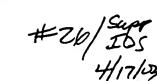
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Respectfully submitted,

Date: 1-15-2002





IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

	09/602,395
Patent Application Serial No	June 22, 2000
Filing DateInventor	John T. Moore
Inventor	Micron Technology, Inc.
Assignee	2813
Group Art Unit	T. Pham
Examiner	MI22-1384
Attorney Docket No. Title: Methods of Forming Oxide Regions Over Semico	onductor Substrates

Assistant Commissioner for Patents Washington, D.C. 20231

CERTIFICATE OF FACSIMILE TRANSMISSION UNDER 37 CFR 1.8

I hereby certify that the following papers are being facsimile transmitted to the Patent and Trademark Office at (703) 872-9318 on the date shown below:

Supplemental Information Disclosure Statement w/PTO-1449 and 1. copy of cited reference

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NUMBER OF PAGES IN FACSIMILE: 12

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758	AA	6,413,881 BI	07-2002	Aronowitz et al.					
TS8	AB	6,110,780	08-2000	Yu et al.		<u> </u>			
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757	AB	6,080,629	06-2000	Gardner et al.					
759	AC	5,970,345	10-1999	Hattangady et al.		ļ			
75p	AD	5,885,877	03-1999	Gardner et al.		ļ			
TSP	AE	6,323,114 B1	11-2001	Hattangady et al.		ļ		OCT 15 2001	
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758	AC	5,318,924	06-1994	Lin et al.					
788	AD	5,449,631	09-1995	Giewont et al.					
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37	AD	6,136,636	10/00	Wu					
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r	TSP	АВ	5,436,481	07/95	Egawa et al.			257	324	1/199	4		
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	TSP	AK	5,719,083	40/97	Komatsu	7.9	8	438	652	6/19	<u>95</u>		
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